ELSEVIER

Ultramicroscopy 58 (1995) 443–445

ultramicroscopy

Author index to volume 58

Allard, L.F., see Völkl 58 (1995) 97
Atici, Y. and D. Cherns, Observation of crystal distortions in SiGe/Si superlattice using a new application of large-angle convergent-beam electron diffraction 58 (1995) 435

Baba, T., see Horita 58 (1995) 327
Bacher, A., see Rübenkamm 58 (1995) 337
Bachmann, L., see Rübenkamm 58 (1995) 337
Baumann, F.H., see Kisielowski 58 (1995) 131
Baumeister, W., see Rübenkamm 58 (1995) 337
Behal, S.K., see Hunt 58 (1995) 55
Bonnet, N., Erratum to "Preliminary investigation of two methods for the automatic handling of multivariate maps in microanalysis" [Ultramicroscopy 57 (1995) 17–27] 58 (1995) 441
Booker, G.R., see Konkol 58 (1995) 233
Böttcher, B., Electron cryo-microscopy of graphite in amorphous ice 58 (1995) 417
Boudet, A., see Tournier-Lasserve 58 (1995) 123
Brandow, S.L., see Turner 58 (1995) 425
Brandt, J., see Rübenkamm 58 (1995) 337
Braun, N., see Rübenkamm 58 (1995) 337

Cantow, H-J., see Wawkuschewski 58 (1995) 185
Carragher, B.O., see Whittaker 58 (1995) 245
Castell, M.R., see Perovic 58 (1995) 104
Chang, C., see Turner 58 (1995) 425
Chen, C.Y. and W.M. Stobbs, The α-fringe contrast of thin twins in relation to the anomalous weak-beam contrast of stacking faults 58 (1995) 289
Cherns, D., see Atici 58 (1995) 435
Chevalier, J.P., see Hÿtch 58 (1995) 114
Cole, J.S.W., see Perovic 58 (1995) 104
Colliex, C., see Tencé 58 (1995) 42
Corbett, J.M., see Robertson 58 (1995) 175
Cowley, J.M., M.S. Hansen and S.-Y. Wang, Imaging modes with an annular detector in STEM 58 (1995) 18
Cowley, J.M., see Gajdardziska-Josifovska 58 (1995) 65
Cowley, J.M., see Mankos 58 (1995) 87
Crämer, K., see Wawkuschewski 58 (1995) 185
Crozier, P.A., Quantitative elemental mapping of materials by energy-filtered imaging 58 (1995) 157
Currie, J.E., see Robertson 58 (1995) 175

Datye, A., see Völkl 58 (1995) 97
Daykin, A.C. and A.K. Petford-Long, Quantitative mapping of the magnetic induction distribution using Foucault images formed in a transmission electron microscope 58 (1995) 365
Disko, M.M., see Hunt 58 (1995) 55
Door, R. and D. Gängler, Multiple least-squares fitting for quantitative electron energy-loss spectroscopy – an experimental investigation using standard specimens 58 (1995) 197

Frank, J., see Ramani Lata 58 (1995) 381
Frank, J., see Liu 58 (1995) 393
Frost, B., see Völkl 58 (1995) 97

Gaber, B.P., see Turner 58 (1995) 425
Gajdardziska-Josifovska, M., J.K. Weiss and J.M. Cowley, Studies of Mo/Si multilayers with coherent electron beams 58 (1995) 65
Gängler, D., see Door 58 (1995) 197
Garcia, N., see Vu Thien Binh 58 (1995) 307

Hammel, M. and H. Rose, Optimum rotationally symmetric detector configurations for phase-contrast imaging in scanning transmission electron microscopy 58 (1995) 403
Hansen, M.S., see Cowley 58 (1995) 18
Harscher, A., G. Lang and H. Lichte, Interpretable resolution of 0.2 nm at 100 kV using electron holography 58 (1995) 79
Haskel, D., M. Sarikaya, M. Qian and E.A. Stern, EXELFS as a tool for quantifying phase distributions in materials 58 (1995) 353
Higgs, A.A., see Mankos 58 (1995) 87
Hillyard, S. and J. Silcox, Detector geometry, thermal diffuse scattering and strain effects in ADF STEM imaging 58 (1995) 6

Elsevier Science B.V.

Hoffmann, H., see Schuhrke 58 (1995) 319
Horita, Z., S. Matsumura and T. Baba, General formulation for ALCHEMI 58 (1995) 327
Howie, A., see Perovic 58 (1995) 104
Hunt, J.A., M.M. Disko, S.K. Behal and R.D. Leapman, Electron energy-loss chemical imaging of polymer phases 58 (1995) 55
Hÿtch, M.J. and J.P. Chevalier, On the breakdown of Friedel's Law for coherent microdiffraction from amorphous materials 58 (1995) 114

Isaacson, M., see Klotzkin 58 (1995) 261

Kim, Y., see Kisielowski 58 (1995) 131
Kisielowski, C., P. Schwander, F.H. Baumann, M. Seibt, Y. Kim and A. Ourmazd, An approach to quantitative high-resolution transmission electron microscopy of crystalline materials 58 (1995) 131
Klotzkin, D. and M. Isaacson, Determination of Cr particle sizes in thin dilute Cr-in-Cu films from measurement statistics 58 (1995) 261
Konkol, A., G.R. Booker and P.R. Wilshaw, Backscattered electron contrast on cross sections of interfaces and multilayers in the scanning electron microscope 58 (1995) 233
Kurnikov, I., see Nevernov 58 (1995) 269

Lakis, R.E., see Lyman 58 (1995) 25
Lang, G., see Harscher 58 (1995) 79
Lavoie, C., see Perovic 58 (1995) 104
Leapman, R.D., see Hunt 58 (1995) 55
Leifer, K., see Stadelmann 58 (1995) 35
Lichte, H., see Harscher 58 (1995) 79
Liu, Y., P.A. Penczek, B.F. McEwen and J. Frank, A marker-free alignment method for electron tomography 58 (1995) 393
Lyman, C.E., R.E. Lakis and H.G. Stenger, Jr., X-ray emission spectrometry of phase separation in Pt–Rh nanoparticles for nitric oxide reduction 58 (1995) 25

Magonov, S.N., see Wawkuschewski 58 (1995) 185
Mankos, M., A.A. Higgs, M.R. Scheinfein and J.M. Cowley, Far-out-of-focus electron holography in a dedicated FEG STEM 58 (1995) 87
Matsumura, S., see Horita 58 (1995) 327
Mattei, G. and A.M. Mazzone, Analysis of irradiated Ag and Si by molecular dynamics and simulated HREM images 58 (1995) 223
Mazzone, A.M., see Mattei 58 (1995) 223
McEwen, B.F., see Liu 58 (1995) 393
Milligan, R.A., see Whittaker 58 (1995) 245
Murphy, D.B., see Turner 58 (1995) 425

Nevernov, I., I. Kurnikov and C. Nicolini, Mechanical interactions in STM imaging of large insulating adsorbates 58 (1995) 269
Nicolini, C., see Nevernov 58 (1995) 269

Ourmazd, A., see Kisielowski 58 (1995) 131

Penczek, P.A., see Ramani Lata 58 (1995) 381
Penczek, P.A., see Liu 58 (1995) 393
Perovic, D.D., M.R. Castell, A. Howie, C. Lavoie, T. Tiedje and J.S.W. Cole, Field-emission SEM imaging of compositional and doping layer semiconductor superlattices 58 (1995) 104
Petford-Long, A.K., see Daykin 58 (1995) 365

Qian, M., see Haskel 58 (1995) 353
Quartuccio, M., see Tencé 58 (1995) 42

Ramani Lata, K., P.A. Penczek and J. Frank, Automatic particle picking from electron micrographs 58 (1995) 381
Robertson, M.D., J.E. Currie, J.M. Corbett and J.B. Webb, Determination of elastic strains in epitaxial layers by HREM 58 (1995) 175
Rose, H., see Hammel 58 (1995) 403
Rossouw, C.J., Incoherent contrast under dynamical diffraction conditions 58 (1995) 211
Rübenkamm, E., N. Braun, L. Bachmann, A. Bacher, J. Brandt, W. Baumeister and S. Weinkauf, Quantitative evaluation of heavy metal decoration on protein molecules: contrast, specificity and resolution 58 (1995) 337

Sarikaya, M., see Haskel 58 (1995) 353
Sato, K., see Stobbs 58 (1995) 275
Saxton, W.O., Simple prescriptions for estimating three-fold astigmatism 58 (1995) 239
Scheinfein, M.R., see Mankos 58 (1995) 87
Schuhrke, T., J. Zweck and H. Hoffmann, The problem of absorption in the Fresnel fringe analysis 58 (1995) 319
Schwander, P., see Kisielowski 58 (1995) 131
Seibt, M., see Kisielowski 58 (1995) 131
Semet, V., see Vu Thien Binh 58 (1995) 307
Silcox, J., see Hillyard 58 (1995) 6
Smith, D.J., Foreword to Microscopy with Field Emission Electron Sources 58 (1995) vii
Sopéna, P., see Tournier-Lasserve 58 (1995) 123
Stadelmann, P., K. Leifer and C. Verdon, EDS and EELS using a TEM-FEG microscope 58 (1995) 35
Stenger, Jr., H.G., see Lyman 58 (1995) 25
Stern, E.A., see Haskel 58 (1995) 353

Stobbs, S.H., K. Sato and W.M. Stobbs, The HREM use of the FEGTEM for the study of interfaces 58 (1995) 275
Stobbs, W.M., see Stobbs 58 (1995) 275
Stobbs, W.M., see Chen 58 (1995) 289

Tencé, M., M. Quartuccio and C. Colliex, PEELS compositional profiling and mapping at nanometer spatial resolution 58 (1995) 42
Tiedje, T., see Perovic 58 (1995) 104
Tournier-Lasserve, V., A. Boudet and P. Sopéna, Artefacts and their healing in ultramicrotomy of side-chain liquid-crystal polymers 58 (1995) 123
Turner, D.C., C. Chang, S.L. Brandow, D.B. Murphy and B.P. Gaber, Use of a repositionable substrate to acquire and compare distinct atomic force microscope images of a field of microtubules 58 (1995) 425

Verdon, C., see Stadelmann 58 (1995) 35
Völkl, E., L.F. Allard, A. Datye and B. Frost, Advanced electron holography: a new algorithm for image processing and a standardized quality test for the FEG electron microscope 58 (1995) 97
Von Harrach, H.S., Instrumental factors in high-resolution FEG STEM 58 (1995) 1
Vu Thien Binh, V. Semet and N. Garcia, Nanometric observations at low energy by Fresnel projection microscopy: carbon and polymer fibres 58 (1995) 307

Wang, S.-Y., see Cowley 58 (1995) 18
Wawkuschewski, A., K. Crämer, H-J. Cantow and S.N. Magonov, Optimization of experiment in scanning force microscopy of polymers 58 (1995) 185
Webb, J.B., see Robertson 58 (1995) 175
Weinkauf, S., see Rübenkamm 58 (1995) 337
Weiss, J.K., see Gajdardziska-Josifovska 58 (1995) 65
Whittaker, M., B.O. Carragher and R.A. Milligan, PHOELIX: a package for semi-automated helical reconstruction 58 (1995) 245
Wilshaw, P.R., see Konkol 58 (1995) 233

Zweck, J., see Schuhrke 58 (1995) 319

ELSEVIER

Ultramicroscopy 58 (1995) 448–450

ultramicroscopy

Subject index to volume 58

Atomic force microscopy (AFM)

Optimization of experiment in scanning force microscopy of polymers, *Wawkuschewski, Crämer, Cantow and Magonov* 58 (1995) 185

Use of a repositionable substrate to acquire and compare distinct atomic force microscope images of a field of microtubules, *Turner, Chang, Brandow, Murphy and Gaber* 58 (1995) 425

Contrast transfer theory

The α-fringe contrast of thin twins in relation to the anomalous weak-beam contrast of stacking faults, *Chen and Stobbs* 58 (1995) 289

The problem of absorption in the Fresnel fringe analysis, *Schuhrke, Zweck and Hoffmann* 58 (1995) 319

Convergent beam electron diffraction (CBED)

Incoherent contrast under dynamical diffraction conditions, *Rossouw* 58 (1995) 211

Observation of crystal distortions in SiGe/Si superlattice using a new application of large-angle convergent-beam electron diffraction, *Atici and Cherns* 58 (1995) 435

Cryomicroscopic methods

Electron cryo-microscopy of graphite in amorphous ice, *Böttcher* 58 (1995) 417

Data processing / image processing

Advanced electron holography: a new algorithm for image processing and a standardized quality test for the FEG electron microscope, *Völkl, Allard, Datye and Frost* 58 (1995) 97

Determination of elastic strains in epitaxial layers by HREM, *Robertson, Currie, Corbett and Webb* 58 (1995) 175

Multiple least-squares fitting for quantitative electron energy-loss spectroscopy – an experimental investigation using standard specimens, *Door and Gängler* 58 (1995) 197

Automatic particle picking from electron micrographs, *Ramani Lata, Penczek and Frank* 58 (1995) 381

Erratum to "Preliminary investigation of two methods for the automatic handling of multivariate maps in microanalysis" [Ultramicroscopy 57 (1995) 17–27], *Bonnet* 58 (1995) 441

Editorials, Announcements, Comments, Reports, Historical notes

Foreword to Microscopy with Field Emission Electron Sources, *Smith* 58 (1995) vii

Electron diffraction

Studies of Mo/Si multilayers with coherent electron beams, *Gajdardziska-Josifovska, Weiss and Cowley* 58 (1995) 65

On the breakdown of Friedel's Law for coherent microdiffraction from amorphous materials, *Hÿtch and Chevalier* 58 (1995) 114

Electron diffraction and elastic scattering theory, image simulation

Detector geometry, thermal diffuse scattering and strain effects in ADF STEM imaging, *Hillyard and Silcox* 58 (1995) 6

Incoherent contrast under dynamical diffraction conditions, *Rossouw* 58 (1995) 211

Analysis of irradiated Ag and Si by molecular dynamics and simulated HREM images, *Mattei and Mazzone* 58 (1995) 223

The problem of absorption in the Fresnel fringe analysis, *Schuhrke, Zweck and Hoffmann* 58 (1995) 319

Electron energy loss spectroscopy (EELS)

EDS and EELS using a TEM-FEG microscope, *Stadelmann, Leifer and Verdon* 58 (1995) 35

PEELS compositional profiling and mapping at nanometer spatial resolution, *Tencé, Quartuccio and Colliex* 58 (1995) 42

Electron energy-loss chemical imaging of polymer phases, *Hunt, Disko, Behal and Leapman* 58 (1995) 55

Elsevier Science B.V.

Studies of Mo/Si multilayers with coherent electron beams, *Gajdardziska-Josifovska, Weiss and Cowley* 58 (1995) 65
Multiple least-squares fitting for quantitative electron energy-loss spectroscopy – an experimental investigation using standard specimens, *Door and Gängler* 58 (1995) 197
EXELFS as a tool for quantifying phase distributions in materials, *Haskel, Sarikaya, Qian and Stern* 58 (1995) 353

Electron microscope design and characterization
Instrumental factors in high-resolution FEG STEM, *Von Harrach* 58 (1995) 1
Simple prescriptions for estimating three-fold astigmatism, *Saxton* 58 (1995) 239

Energy-filtered imaging and diffraction
Quantitative elemental mapping of materials by energy-filtered imaging, *Crozier* 58 (1995) 157

High resolution transmission electron microscopy (HRTEM)
An approach to quantitative high-resolution transmission electron microscopy of crystalline materials, *Kisielowski, Schwander, Baumann, Seibt, Kim and Ourmazd* 58 (1995) 131
Determination of elastic strains in epitaxial layers by HREM, *Robertson, Currie, Corbett and Webb* 58 (1995) 175
The HREM use of the FEGTEM for the study of interfaces, *Stobbs, Sato and Stobbs* 58 (1995) 275

Holography
Interpretable resolution of 0.2 nm at 100 kV using electron holography, *Harscher, Lang and Lichte* 58 (1995) 79
Far-out-of-focus electron holography in a dedicated FEG STEM, *Mankos, Higgs, Scheinfein and Cowley* 58 (1995) 87
Advanced electron holography: a new algorithm for image processing and a standardized quality test for the FEG electron microscope, *Völkl, Allard, Datye and Frost* 58 (1995) 97

Image detectors
Detector geometry, thermal diffuse scattering and strain effects in ADF STEM imaging, *Hillyard and Silcox* 58 (1995) 6
Optimum rotationally symmetric detector configurations for phase-contrast imaging in scanning transmission electron microscopy, *Hammel and Rose* 58 (1995) 403

Inelastic electron scattering theory
General formulation for ALCHEMI, *Horita, Matsumura and Baba* 58 (1995) 327

Instrument control and alignment
Simple prescriptions for estimating three-fold astigmatism, *Saxton* 58 (1995) 239

Low energy electron microscopy and diffraction (LEEM and LEED)
Nanometric observations at low energy by Fresnel projection microscopy: carbon and polymer fibres, *Vu Thien Binh, Semet and Garcia* 58 (1995) 307

Microscopic methods, specifically for biological specimens
PHOELIX: a package for semi-automated helical reconstruction, *Whittaker, Carragher and Milligan* 58 (1995) 245
Quantitative evaluation of heavy metal decoration on protein molecules: contrast, specificity and resolution, *Rübenkamm, Braun, Bachmann, Bacher, Brandt, Baumeister and Weinkauf* 58 (1995) 337
Automatic particle picking from electron micrographs, *Ramani Lata, Penczek and Frank* 58 (1995) 381

Microscopic methods, specifically for solid interfaces and multilayers
Studies of Mo/Si multilayers with coherent electron beams, *Gajdardziska-Josifovska, Weiss and Cowley* 58 (1995) 65
Field-emission SEM imaging of compositional and doping layer semiconductor superlattices, *Perovic, Castell, Howie, Lavoie, Tiedje and Cole* 58 (1995) 104
Backscattered electron contrast on cross sections of interfaces and multilayers in the scanning electron microscope, *Konkol, Booker and Wilshaw* 58 (1995) 233
The HREM use of the FEGTEM for the study of interfaces, *Stobbs, Sato and Stobbs* 58 (1995) 275
Observation of crystal distortions in SiGe/Si superlattice using a new application of large-angle convergent-beam electron diffraction, *Atici and Cherns* 58 (1995) 435

Miscellaneous methods
The α-fringe contrast of thin twins in relation to the anomalous weak-beam contrast of stacking faults, *Chen and Stobbs* 58 (1995) 289
Nanometric observations at low energy by Fresnel projection microscopy: carbon and polymer fibres, *Vu Thien Binh, Semet and Garcia* 58 (1995) 307
The problem of absorption in the Fresnel fringe analysis, *Schuhrke, Zweck and Hoffmann* 58 (1995) 319

Quantitative mapping of the magnetic induction distribution using Foucault images formed in a transmission electron microscope, *Daykin and Petford-Long* 58 (1995) 365

Scanning electron microscopy (SEM)
Field-emission SEM imaging of compositional and doping layer semiconductor superlattices, *Perovic, Castell, Howie, Lavoie, Tiedje and Cole* 58 (1995) 104
Backscattered electron contrast on cross sections of interfaces and multilayers in the scanning electron microscope, *Konkol, Booker and Wilshaw* 58 (1995) 233

Scanning transmission electron microscopy (STEM)
Instrumental factors in high-resolution FEG STEM, *Von Harrach* 58 (1995) 1
Detector geometry, thermal diffuse scattering and strain effects in ADF STEM imaging, *Hillyard and Silcox* 58 (1995) 6
Imaging modes with an annular detector in STEM, *Cowley, Hansen and Wang* 58 (1995) 18
Far-out-of-focus electron holography in a dedicated FEG STEM, *Mankos, Higgs, Scheinfein and Cowley* 58 (1995) 87
Optimum rotationally symmetric detector configurations for phase-contrast imaging in scanning transmission electron microscopy, *Hammel and Rose* 58 (1995) 403

Scanning tunneling microscopy (STM)
Mechanical interactions in STM imaging of large insulating adsorbates, *Nevernov, Kurnikov and Nicolini* 58 (1995) 269

Specimen preparation and handling
Artefacts and their healing in ultramicrotomy of side-chain liquid-crystal polymers, *Tournier-Lasserve, Boudet and Sopéna* 58 (1995) 123

Tip scanning instrument design and characterization
Use of a repositionable substrate to acquire and compare distinct atomic force microscope images of a field of microtubules, *Turner, Chang, Brandow, Murphy and Gaber* 58 (1995) 425

Three-dimensional reconstruction and stereo microscopy
PHOELIX: a package for semi-automated helical reconstruction, *Whittaker, Carragher and Milligan* 58 (1995) 245
A marker-free alignment method for electron tomography, *Liu, Penczek, McEwen and Frank* 58 (1995) 393

X-ray microanalysis
X-ray emission spectrometry of phase separation in Pt–Rh nanoparticles for nitric oxide reduction, *Lyman, Lakis and Stenger, Jr.* 58 (1995) 25
EDS and EELS using a TEM-FEG microscope, *Stadelmann, Leifer and Verdon* 58 (1995) 35
Determination of Cr particle sizes in thin dilute Cr-in-Cu films from measurement statistics, *Klotzkin and Isaacson* 58 (1995) 261
General formulation for ALCHEMI, *Horita, Matsumura and Baba* 58 (1995) 327